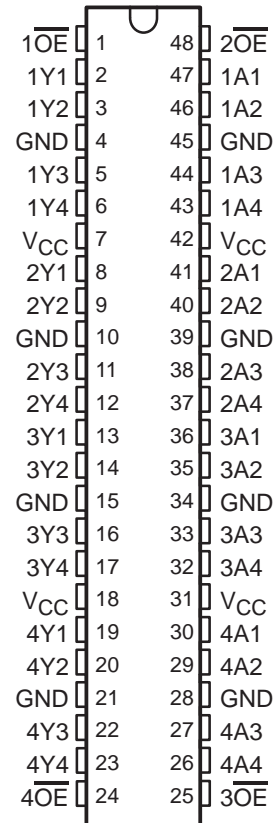


SN54AHC16244, SN74AHC16244 16-BIT BUFFERS/DRIVERS WITH 3-STATE OUTPUTS

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- Members of the Texas Instruments *Widebus™* Family
- *EPIC™* (Enhanced-Performance Implanted CMOS) Process
- Operating Range 2-V to 5.5-V V_{CC}
- Distributed V_{CC} and GND Pins Minimize High-Speed Switching Noise
- Flow-Through Architecture Optimizes PCB Layout
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Package Options Include Plastic Shrink Small-Outline (DL), Thin Shrink Small-Outline (DGG), and Thin Very Small-Outline (DGV) Packages and 380-mil Fine-Pitch Ceramic Flat (WD) Package Using 25-mil Center-to-Center Spacings

SN54AHC16244 . . . WD PACKAGE
SN74AHC16244 . . . DGG, DGV, OR DL PACKAGE
(TOP VIEW)



description

The 'AHC16244 devices are 16-bit buffers and line drivers designed specifically to improve the performance and density of 3-state memory address drivers, clock drivers, and bus-oriented receivers and transmitters.

These devices can be used as four 4-bit buffers, two 8-bit buffers, or one 16-bit buffer. They provide true outputs and symmetrical active-low output-enable (\overline{OE}) inputs.

To ensure the high-impedance state during power up or power down, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN54AHC16244 is characterized for operation over the full military temperature range of -55°C to 125°C . The SN74AHC16244 is characterized for operation from -40°C to 85°C .

FUNCTION TABLE
(each 4-bit buffer/driver)

INPUTS		OUTPUT
\overline{OE}	A	Y
L	H	H
L	L	L
H	X	Z



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 **TEXAS
INSTRUMENTS**

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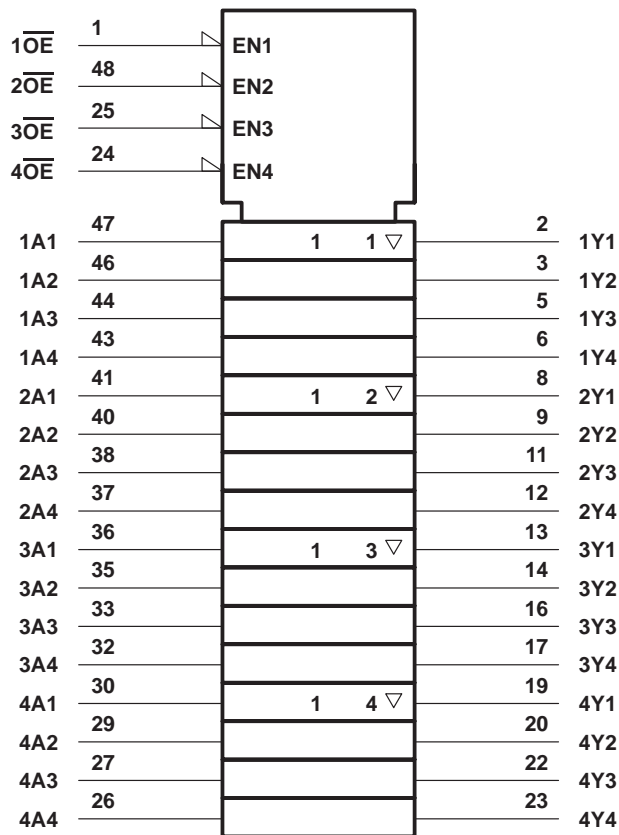
SN54AHC16244, SN74AHC16244

16-BIT BUFFERS/DRIVERS

WITH 3-STATE OUTPUTS

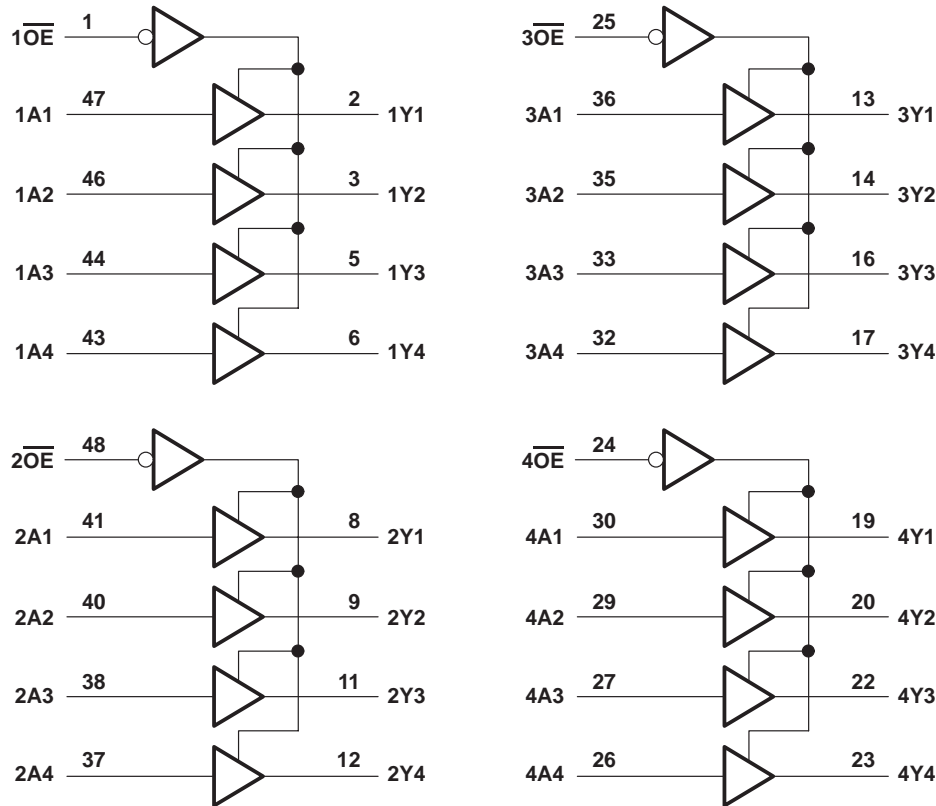
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logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V_{CC}	-0.5 V to 7 V
Input voltage range, V_I (see Note 1)	-0.5 V to 7 V
Output voltage range, V_O (see Note 1)	-0.5 V to $V_{CC} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	-20 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$)	± 20 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})	± 25 mA
Continuous current through each V_{CC} or GND	± 75 mA
Package thermal impedance, θ_{JA} (see Note 2):	
DGG package	70°C/W
DGV package	58°C/W
DL package	63°C/W
Storage temperature range, T_{stg}	-65°C to 150°C

† Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.
 2. The package thermal impedance is calculated in accordance with JESD 51.

SN54AHC16244, SN74AHC16244

16-BIT BUFFERS/DRIVERS

WITH 3-STATE OUTPUTS

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recommended operating conditions (see Note 3)

		SN54AHC16244		SN74AHC16244		UNIT
		MIN	MAX	MIN	MAX	
V _{CC}	Supply voltage	2	5.5	2	5.5	V
V _{IH}	High-level input voltage	V _{CC} = 2 V		1.5		V
		V _{CC} = 3 V		2.1		
		V _{CC} = 5.5 V		3.85		
V _{IL}	Low-level input voltage	V _{CC} = 2 V		0.5		V
		V _{CC} = 3 V		0.9		
		V _{CC} = 5.5 V		1.65		
V _I	Input voltage	0	5.5	0	5.5	V
V _O	Output voltage	0	V _{CC}	0	V _{CC}	V
I _{OH}	High-level output current	V _{CC} = 2 V		-50		μA
		V _{CC} = 3.3 ± 0.3 V		-4		
		V _{CC} = 5 ± 0.5 V		-8		
I _{OL}	Low-level output current	V _{CC} = 2 V		50		μA
		V _{CC} = 3.3 ± 0.3 V		4		
		V _{CC} = 5 ± 0.5 V		8		
Δt/Δv	Input transition rise or fall rate	V _{CC} = 3.3 ± 0.3 V		100		ns/V
		V _{CC} = 5 ± 0.5 V		20		
T _A	Operating free-air temperature	-55	125	-40	85	°C

NOTE 3: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V _{CC}	T _A = 25°C			SN54AHC16244		SN74AHC16244		UNIT
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	
V _{OH}	I _{OH} = -50 μA	2 V	1.9	2	1.9	1.9	V			
		3 V	2.9	3	2.9	2.9				
		4.5 V	4.4	4.5	4.4	4.4				
	I _{OH} = -4 mA	3 V	2.58		2.48	2.48				
		4.5 V	3.94		3.8	3.8				
V _{OL}	I _{OL} = 50 μA	2 V		0.1	0.1	0.1	V			
		3 V		0.1	0.1	0.1				
		4.5 V		0.1	0.1	0.1				
	I _{OL} = 4 mA	3 V		0.36	0.5	0.44				
		4.5 V		0.36	0.5	0.44				
I _I	V _I = V _{CC} or GND	0 V to 5.5 V		±0.1	±1*	±1	μA			
I _{OZ}	V _O = V _{CC} or GND, V _I (OE) = V _{IL} or V _{IH}	5.5 V		±0.25	±2.5	±2.5	μA			
I _{CC}	V _I = V _{CC} or GND, I _O = 0	5.5 V		4	40	40	μA			
C _i	V _I = V _{CC} or GND	5 V		2 10		10	pF			
C _o	V _O = V _{CC} or GND	5 V		3.5			pF			

* On products compliant to MIL-PRF-38535, this parameter is not production tested at V_{CC} = 0 V.

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SN54AHC16244, SN74AHC16244
16-BIT BUFFERS/DRIVERS
WITH 3-STATE OUTPUTS

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switching characteristics over recommended operating free-air temperature range,
 $V_{CC} = 3.3 V \pm 0.3 V$ (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	LOAD CAPACITANCE	$T_A = 25^\circ C$			SN54AHC16244		SN74AHC16244		UNIT
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
t_{PLH}	A	Y	$C_L = 15 \text{ pF}$	5.8*	8.4*		1*	10*	1	10	ns
t_{PHL}				5.8*	8.4*	1*	10*	1	10		
t_{PZH}	\overline{OE}	Y	$C_L = 15 \text{ pF}$	6.6*	10.6*		1*	12.5*	1	12.5	ns
t_{PZL}				6.6*	10.6*	1*	12.5*	1	12.5		
t_{PHZ}	\overline{OE}	Y	$C_L = 15 \text{ pF}$	5*	11.5*		1*	12.5*	1	12.5	ns
t_{PLZ}				5*	11.5*	1*	12.5*	1	12.5		
t_{PLH}	A	Y	$C_L = 50 \text{ pF}$	8.3	11.9		1	13.5	1	13.5	ns
t_{PHL}				8.3	11.9	1	13.5	1	13.5		
t_{PZH}	\overline{OE}	Y	$C_L = 50 \text{ pF}$	9.1	14.1		1	16	1	16	ns
t_{PZL}				9.1	14.1	1	16	1	16		
t_{PHZ}	\overline{OE}	Y	$C_L = 50 \text{ pF}$	10.3	14		1	16	1	16	ns
t_{PLZ}				10.3	14	1	16	1	16		
$t_{sk(o)}$			$C_L = 50 \text{ pF}$			1.5**				1.5	ns

* On products compliant to MIL-PRF-38535, this parameter is not production tested.

** On products compliant to MIL-PRF-38535, this parameter does not apply.

switching characteristics over recommended operating free-air temperature range,
 $V_{CC} = 5 V \pm 0.5 V$ (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	LOAD CAPACITANCE	$T_A = 25^\circ C$			SN54AHC16244		SN74AHC16244		UNIT
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
t_{PLH}	A	Y	$C_L = 15 \text{ pF}$	3.9*	6*		1*	7*	1	6.5	ns
t_{PHL}				3.9*	6*	1*	7*	1	6.5		
t_{PZH}	\overline{OE}	Y	$C_L = 15 \text{ pF}$	4.7*	7.3*		1*	8.5*	1	8.5	ns
t_{PZL}				4.7*	7.3*	1*	8.5*	1	8.5		
t_{PHZ}	\overline{OE}	Y	$C_L = 15 \text{ pF}$	5*	7.2*		1*	8.5*	1	8.5	ns
t_{PLZ}				5*	7.2*	1*	8.5*	1	8.5		
t_{PLH}	A	Y	$C_L = 50 \text{ pF}$	5.4	8		1	9	1	8.5	ns
t_{PHL}				5.4	8	1	9	1	8.5		
t_{PZH}	\overline{OE}	Y	$C_L = 50 \text{ pF}$	6.2	9.3		1	10.5	1	10.5	ns
t_{PZL}				6.2	9.3	1	10.5	1	10.5		
t_{PHZ}	\overline{OE}	Y	$C_L = 50 \text{ pF}$	6.7	9.2		1	10.5	1	10.5	ns
t_{PLZ}				6.7	9.2	1	10.5	1	10.5		
$t_{sk(o)}$			$C_L = 50 \text{ pF}$			1**				1	ns

* On products compliant to MIL-PRF-38535, this parameter is not production tested.

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noise characteristics, $V_{CC} = 5\text{ V}$, $C_L = 50\text{ pF}$, $T_A = 25^\circ\text{C}$ (see Note 4)

PARAMETER	SN74AHC16244			UNIT
	MIN	TYP	MAX	
$V_{OL(P)}$ Quiet output, maximum dynamic V_{OL}		0.5		V
$V_{OL(V)}$ Quiet output, minimum dynamic V_{OL}		-0.2		V
$V_{OH(V)}$ Quiet output, minimum dynamic V_{OH}		4.8		V
$V_{IH(D)}$ High-level dynamic input voltage	3.5			V
$V_{IL(D)}$ Low-level dynamic input voltage			1.5	V

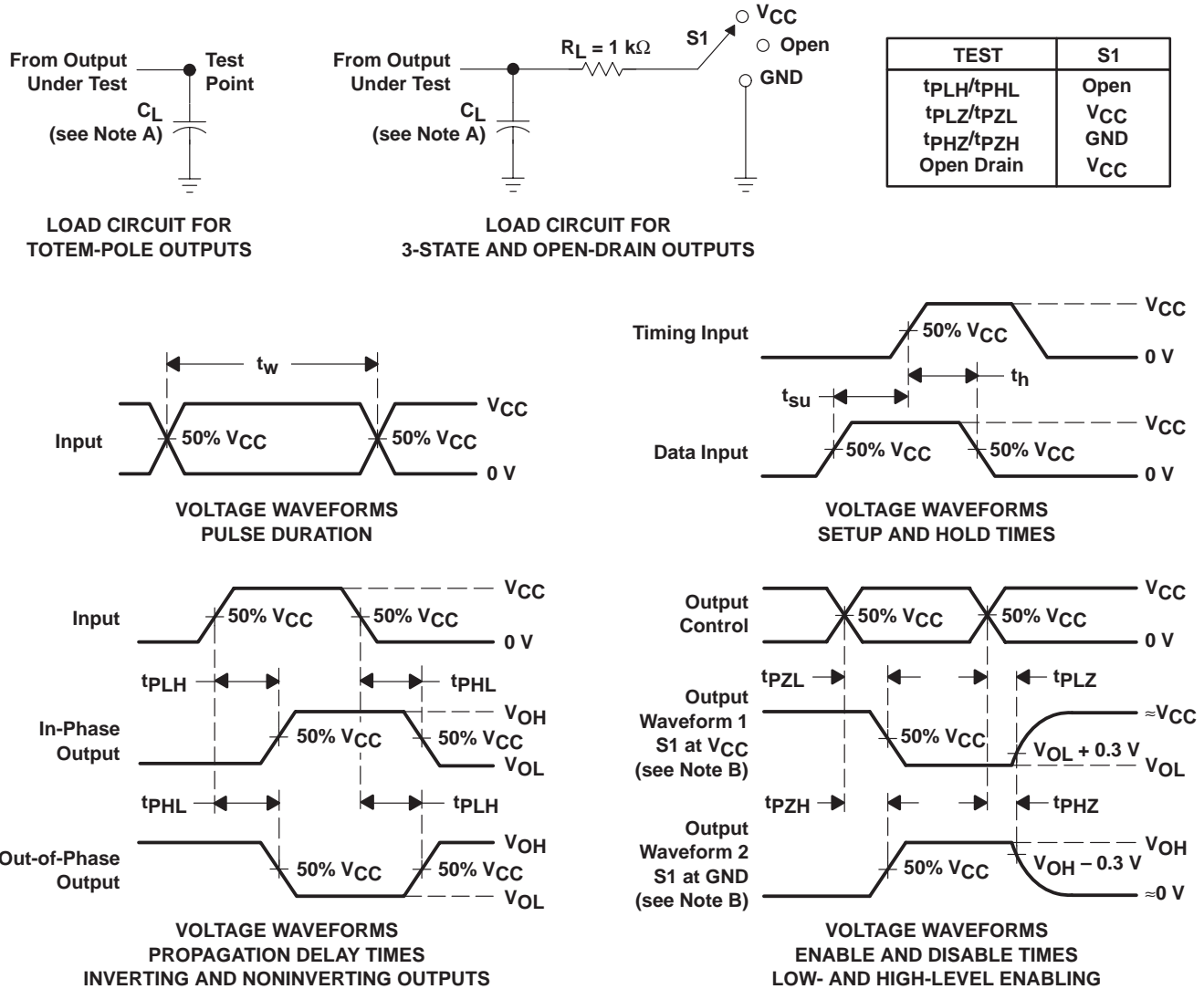
NOTE 4: Characteristics are for surface-mount packages only.

operating characteristics, $V_{CC} = 5\text{ V}$, $T_A = 25^\circ\text{C}$

PARAMETER	TEST CONDITIONS	TYP	UNIT
C_{pd} Power dissipation capacitance	No load, $f = 1\text{ MHz}$	10.5	pF



PARAMETER MEASUREMENT INFORMATION



- NOTES: A. C_L includes probe and jig capacitance.
B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
C. All input pulses are supplied by generators having the following characteristics: PRR ≤ 1 MHz, Z_O = 50 Ω, t_r ≤ 3 ns, t_f ≤ 3 ns.
D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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